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(12) United States Design Patent

Ito et al.

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(54) **SUBSTRATE FOR SPECTROSCOPIC ANALYSIS**

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(30) **Foreign Application Priority Data**

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(51) **LOC (10) Cl.** **24-02**

(52) **U.S. Cl.**
USPC **D24/225**

(58) **Field of Classification Search**
USPC D24/216, 222–226, 231, 232, 169; D10/80, 81; 422/502, 503, 507, 430, 422/560–566, 68.1, 69, 547; 435/288.4, 435/288.3, 289.1, 283.1, 288.2, 288.5; 436/44, 46
CPC B01J 19/0046; B01J 2219/00596; G01N 1/405; G01N 35/00009; G01N 1/312; B01L 2300/0816; B01L 2400/0406; B01L 9/54; B01L 9/06; B01L 9/52; B01L 9/543; B01L 9/00; B01L 3/5085; B01L 3/5027; A61B 5/1427; C12M 1/28; C12M 1/22; C12M 27/02
See application file for complete search history.

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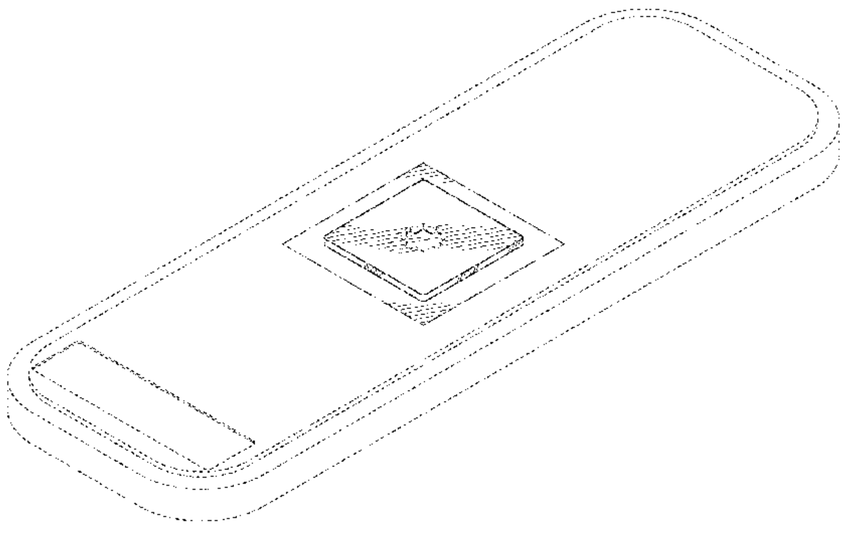

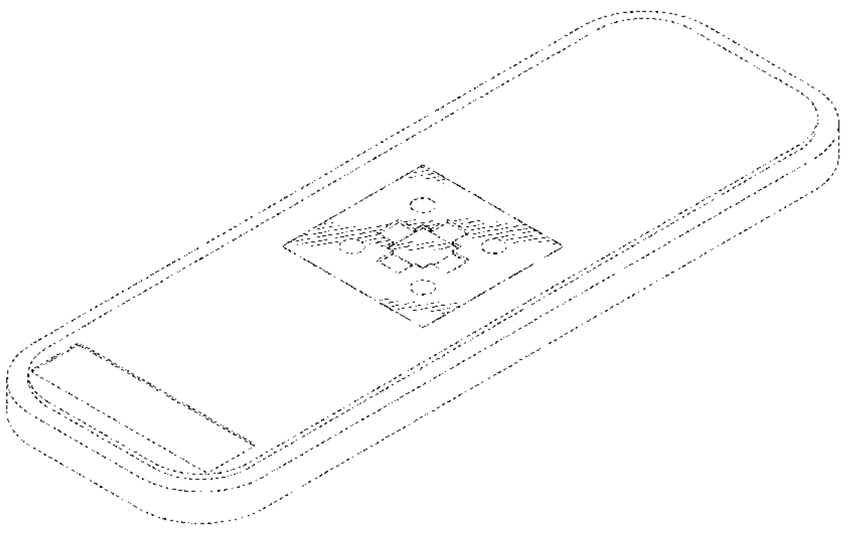

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(57) **CLAIM**

The ornamental design for a substrate for spectroscopic analysis, as shown and described.

DESCRIPTION

FIG. **1** is a front view of a substrate for spectroscopic analysis of our new design.

FIG. **2** is a rear view of the substrate for spectroscopic analysis of FIG. **1**.

FIG. **3** is a top plan view of the substrate for spectroscopic analysis of FIG. **1**.

FIG. **4** is a bottom view of the substrate for spectroscopic analysis of FIG. **1**.

FIG. **5** is a right side view of the substrate for spectroscopic analysis of FIG. **1**.

FIG. **6** is a left side view of the substrate for spectroscopic analysis of FIG. **1**.

FIG. **7** is a perspective of the substrate for spectroscopic analysis of FIG. **1**.

FIG. **8** is a top plan view without the cover part of the substrate for spectroscopic analysis of FIG. **1**.

FIG. **9** is a perspective view without the cover part of the substrate for spectroscopic analysis of FIG. **1**.

FIG. **10** is a sectional view taken along the line **10-10** of the substrate for spectroscopic analysis of FIG. **3**.

FIG. **11** is a sectional view taken along the line **11-11** of the substrate for spectroscopic analysis of FIG. **1**.

FIG. **12** is a sectional view taken along the line **12-12** of the substrate for spectroscopic analysis of FIG. **8**.

FIG. **13** is an enlarged sectional view taken along the line **13-13** of the substrate for spectroscopic analysis of FIG. **10**; and,

FIG. **14** is a reference sectional view taken along the line **10-10** of the substrate for spectroscopic analysis of FIG. **3** in use, wherein the element is inserted in the concave part for element and the glass plate is set above the cover part.

The features shown in dotted lines depict environmental subject matter only and form no part of the claimed design.

The broken lines having alternating long and short segments define bounds of the claimed design and form no part thereof.

The whole of the substrate for spectroscopic analysis is transparent.

1 Claim, 14 Drawing Sheets

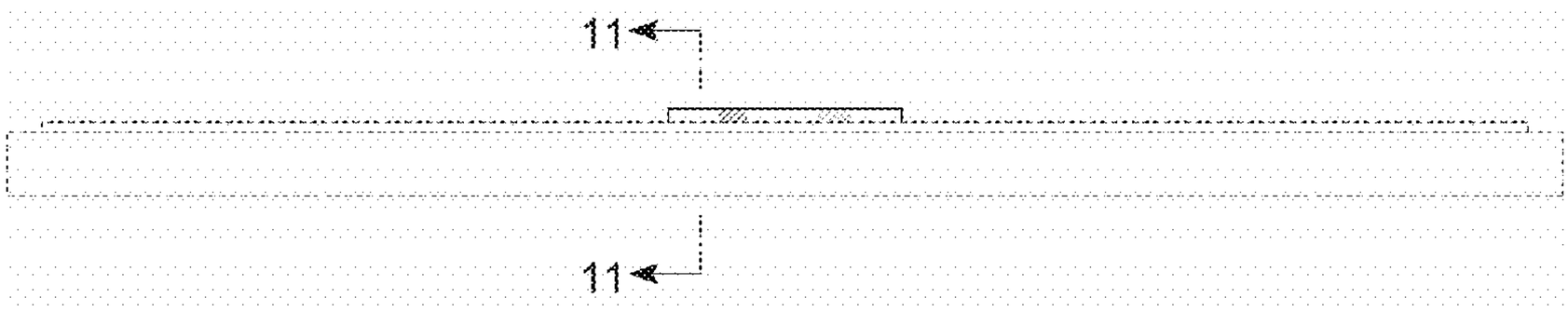

Fig.1

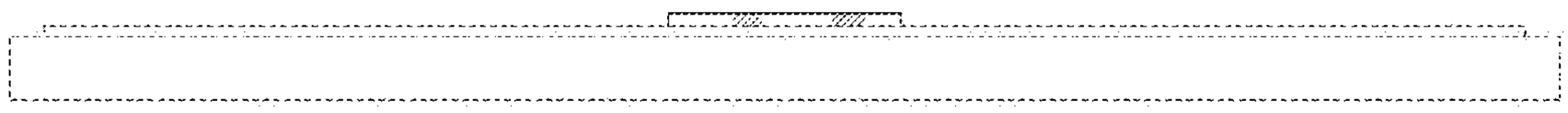

Fig.2

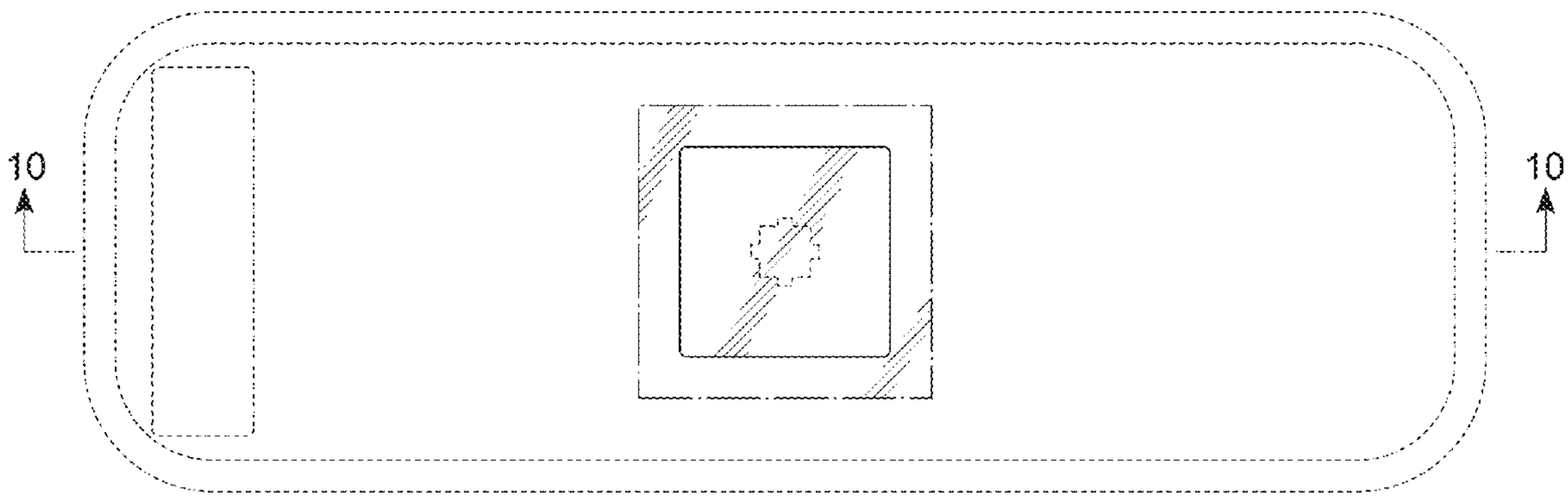

Fig.3

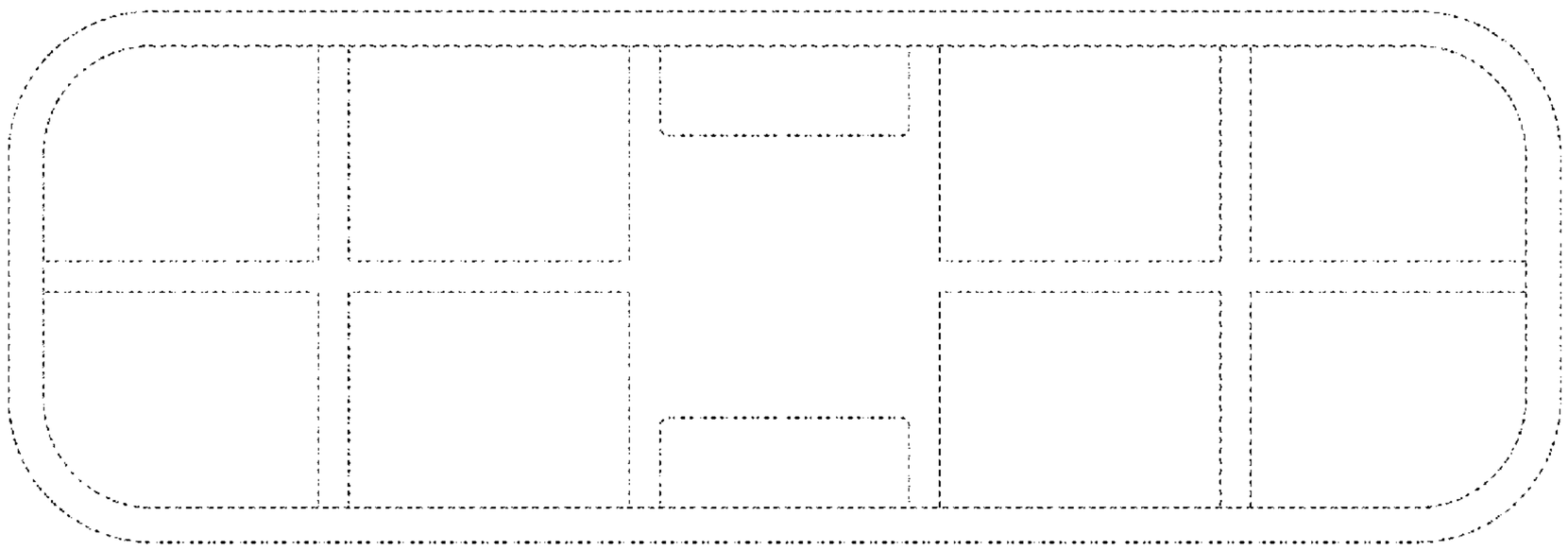

Fig.4

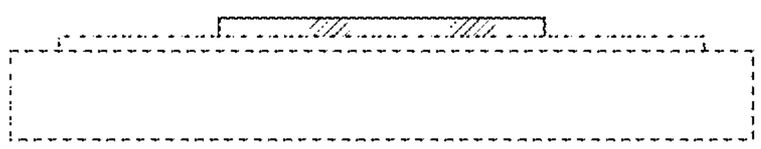

Fig.5

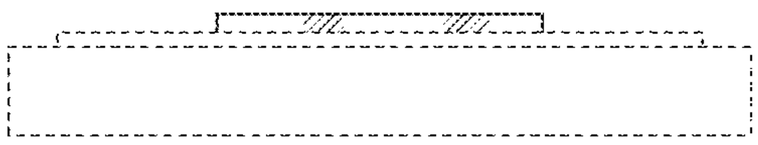

Fig.6

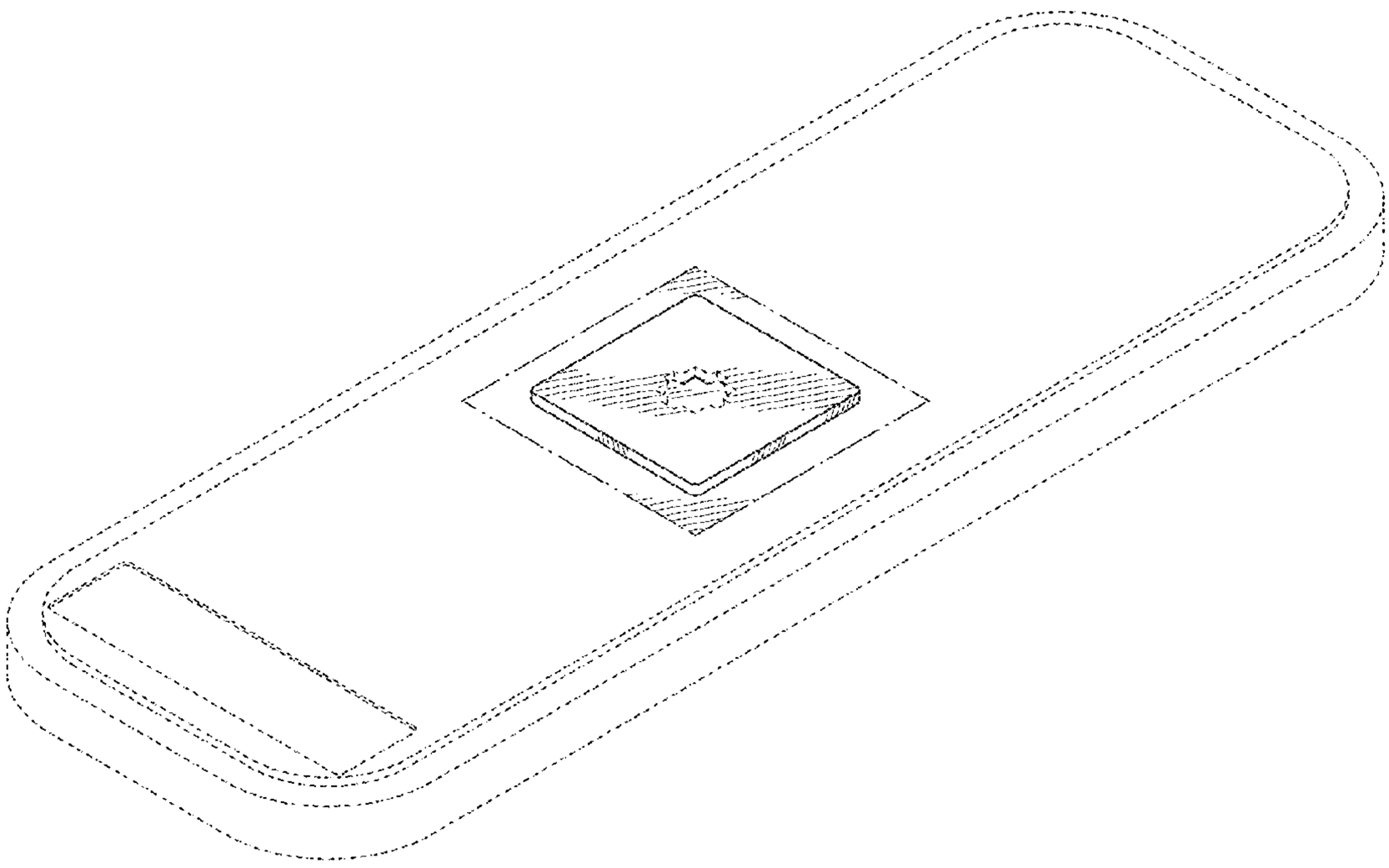

Fig.7

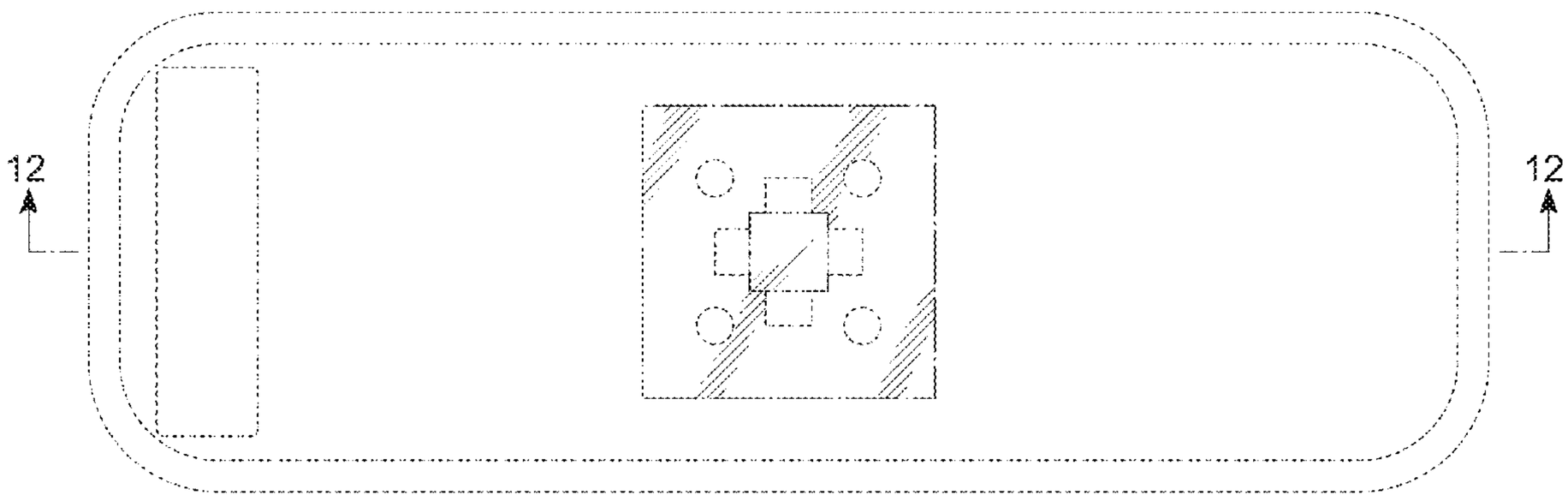

Fig.8

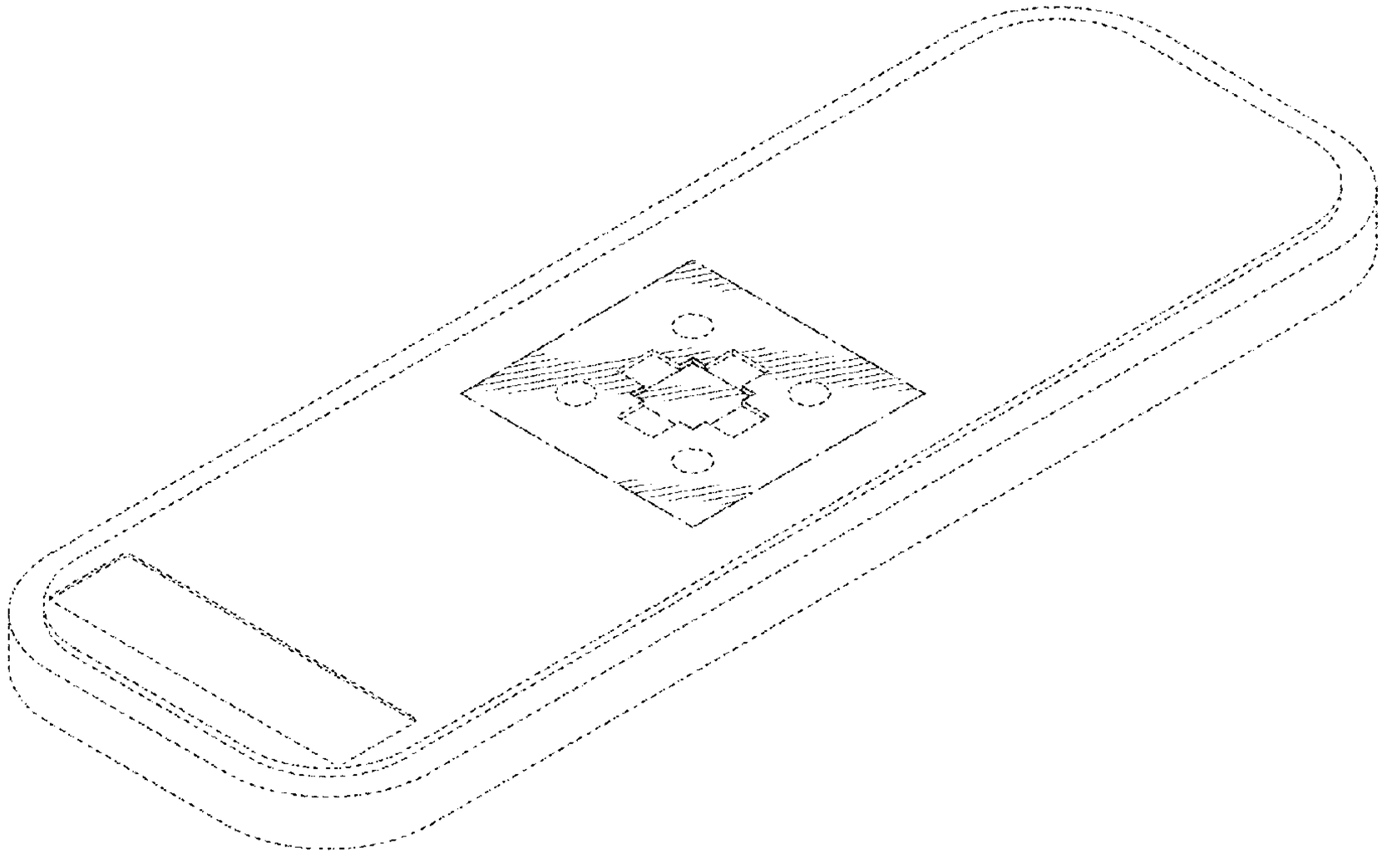

Fig.9

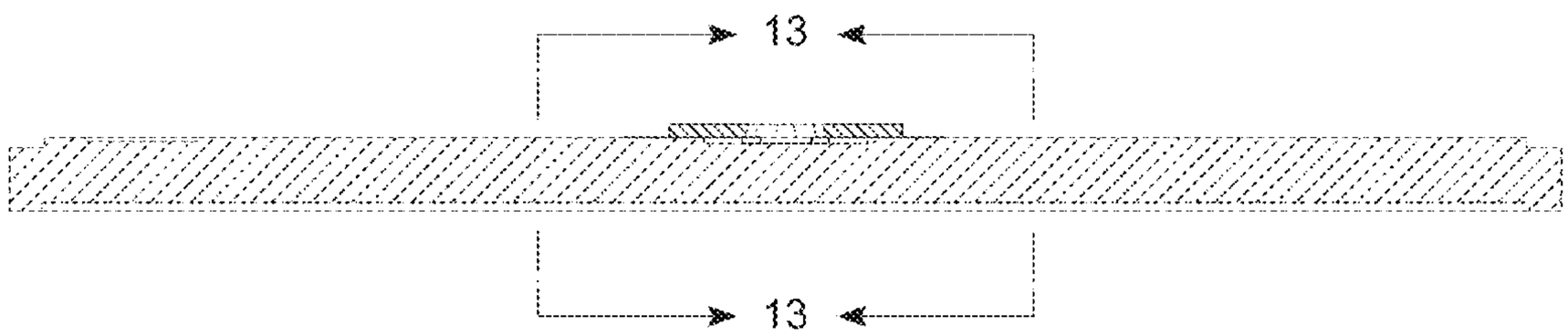

Fig.10

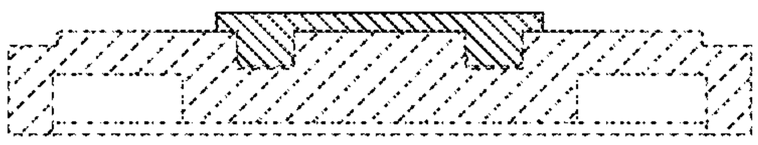

Fig.11

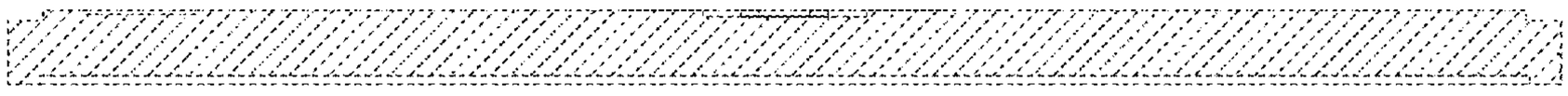

Fig.12

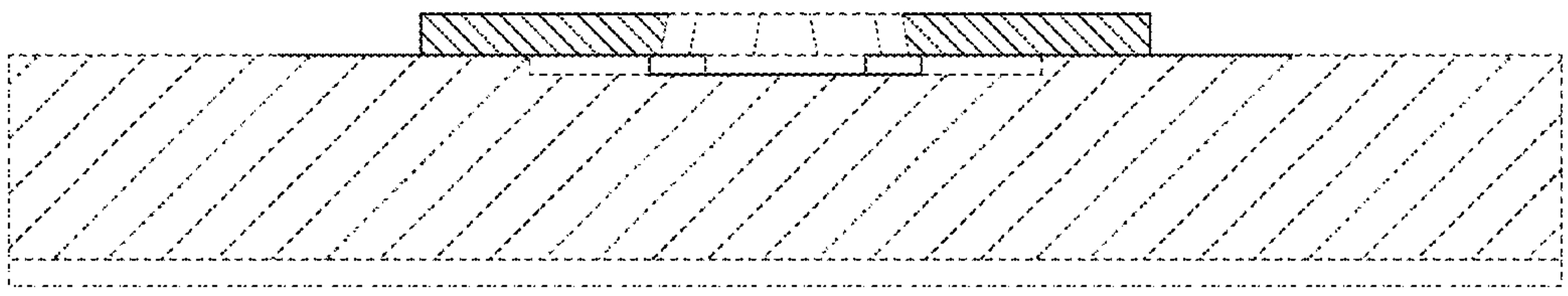

Fig. 13

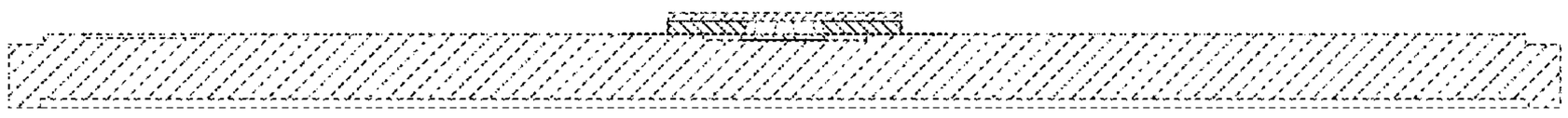

Fig.14